L Number	Hits	Search Text	DB	Time stamp
1	12	(method adj manufacturing adj field adj effect adj transistor) and (substrate adj temperature)	USPAT; US-PGPUB	2003/04/16 08:40
2	13	(method adj manufacturing adj field adj effect adj transistor) and (substrate adj temperature)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/04/16 08:40